

# Search Notes



Application/Control No.

10/069,596

Examiner

Hien Tran

Applicant(s)/Patent under  
Reexamination

NAKAJIMA ET AL.

Art Unit

1764

## SEARCHED

Class	Subclass	Date	Examiner
422	177, 180 171	5/05	mr

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Image cl/sub search / Mr's names search	5/05	mr